

<u>To</u>: Engineering Dept. 6

<u>Mobile LCD Design Center</u>

<u>Mobile Liquid Crystal Display Group</u>

<u>SHARP CORPORATION</u>

 SPEC
 No.
 E L 1 5 4 0 3 4

 I S S U E :
 Apr.
 17 2003

SPECIFICATIONS

| Product Type | LZ9F Series 10000 Gates Gate Array |
|-----------------------|--|
| Model No. | LZ9FD534 |
| XThis spe If you h | ecifications contains <u>21 pages</u> including the cover and appendix. have any objections, please contact us before issuing purchasing order. |
| CUSTOMERS | ACCEPTANCE |
| вү: | PRESENTED BY: Thanks T. TANAKA Dept. General Manager |
| | REVIEWED BY: PREPARED BY: K. J. Shida A. Yokose |

Product Development Dept. 3

Integrated Circuits Group SHARP CORPORATION

LCD LSI Division



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 - · Instrumentation and measuring equipment
 - · Machine tools
 - · Audiovisual equipment
 - · Home appliances
 - · Communication equipment other than for trunk lines
 - (2) Those contemplating using the products covered herein for the following equipment which demands high reliability, should first contact a sales representative of the company and then accept responsibility for incorporating into the design fail-safe operation, redundancy, and other appropriate measures for ensuring reliability and safety of the equipment and the overall system.
 - \cdot Control and safety devices for airplanes, trains, automobiles, and other transportation equipment
 - · Mainframe computers
 - · Traffic control systems
 - · Gas leak detectors and automatic cutoff devices
 - · Rescue and security equipment
 - ·Other safety devices and safety equipment, etc.
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 - · Communications equipment for trunk lines
 - · Control equipment for the nuclear power industry
 - Medical equipment related to life support, etc.
 - (4)Please direct all queries and comments regarding the interpretation of the above three Paragraphs to a sales representative of the company.
- •Please direct all queries regarding the products covered herein to a sales representative of the company.



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1. Introduction

This data sheet is to introduce the specification of LZ9FD534, which is designed by Engineering Dept. 6 Mobile LCD Design Center Mobile Liquid Crystal Display Group Sharp Corporation, timing Control IC for TFT-LCD module.

Functions: Timing Control IC for TFT-LCD module

2. Feature

Process : CMOS

 $\begin{tabular}{lll} Wafer & substrate & : & P-type \ silicon \ substrate \\ \end{tabular}$

Package : 28QFN Materials : Plastics Operating Temperature : $-30^{\circ}\text{C} \sim +85^{\circ}\text{C}$ Propagation delay time : 1.0ns/gate

(Condition : 2-input NAND, Fanout=2, wire length=2mm, supply voltage=3.0V, Operating temperature Topr=25 $^{\circ}$ C)

* REMARK

Not designed or rated as radiation hardened. You cannot rewrite the program.



3. Pin Assignments

| Pin No. | I/0 | Signal Name | Pin No. | I/0 | Signal Name |
|---------|-----|-------------|---------|-----|-------------------|
| 1 | IC | A_ENAI | 15 | _ | GND |
| 2 | IC | A_DATI | 16 | 06M | CLK |
| 3 | ICU | D1 | 17 | 06M | PS |
| 4 | ICU | D2 | 18 | _ | V_{DD} |
| 5 | ICU | PS_SEL | 19 | O2M | A_ENAO |
| 6 | IC | PCI | 20 | O2M | A_DATO |
| 7 | IC | LED_ON | 21 | ICU | RESET |
| 8 | 06M | REV | 22 | IC | LED_PWM |
| 9 | 06M | CLS | 23 | O2M | LED_CTL |
| 10 | O2M | MOD | 24 | _ | V_{DD} |
| 11 | O2M | SPS | 25 | IC | VS |
| 12 | 06M | LP | 26 | IC | HS |
| 13 | 06M | SPL | 27 | IC | DCLK |
| 14 | ICD | TEST | 28 | _ | GND |

IC :Input buffer CMOS level

ICU :Input buffer CMOS level with PULL UP resistance (R=300k $\Omega)$

ICD :Input buffer CMOS level with PULL DOWN resistance (R=300k $\Omega)$

02M :Output buffer (I_{0L} =0.8mA)

06M :Output buffer (I_{0L} =2.4mA)

V_{DD} :Power supply pin

GND :Earth pin



| 4. | Absolute | Maximum | Ratings |
|----|----------|---------|---------|
| | | | |

| Parameter | Symbol | Rating | Unit |
|-----------------------|----------|---------------------|--------------|
| Supply voltage | V_{DD} | $-0.3 \sim +6.0$ | V |
| Input voltage | VI | $-0.3 \sim V_{DD}+$ | -0.3 V |
| Output voltage | V_0 | $-0.3 \sim V_{DD}+$ | ·0.3 V |
| Operating temperature | Topr | $-30 \sim +85$ | $^{\circ}$ C |
| Storage temperature | Tstg | $-55 \sim +150$ | $^{\circ}$ C |

5. Electrical Specifications

5-1. Operating Conditions

| Parameter | Symbol | MIN. | TYP. | MAX. | Unit |
|-----------------------|----------|------|------|------|-------------------------|
| Supply voltage | V_{DD} | +2.6 | +3.0 | +3.6 | V |
| Operating temperature | Topr | -30 | | +85 | $^{\circ}\! \mathbb{C}$ |

5-2. Electrical Characteristics

 $(V_{pp}=+2.6\sim+3.6V, T_{pp}=-30\sim+85^{\circ}C)$

| | | | (V DD - 12. | 0 - 13.00, | 1 Opt — 30 | 100 (| <i></i> |
|---------------------|-------------------|----------------------------|----------------------|------------|---------------------|---------|---------|
| Parameter | Symbol | Test conditions | MIN. | TYP. | MAX. | Unit | # |
| Input"Low" voltage | $ m V_{IL}$ | | | | $V_{DD} \times 0.3$ | V | |
| Input"High"voltage | V_{IH} | | $V_{DD} \times 0.7$ | | | V | 1 |
| Input"High"current | I _{IH1} | $V_{I} = V_{DD}$ | | | 1.0 | μΑ | |
| Input"Low" current | I _{IL1} | $V_I = 0 V$ | | | 1. 0 | μΑ | 2 |
| Input"High"current | I _{IH2} | $V_{I} = V_{DD}$ | 2.0 | | 36. 0 | μΑ | |
| Input"Low" current | I _{IL2} | $V_{I} = 0 V$ | | | 1.0 | μ A | 3 |
| Input"High"current | I _{IH3} | $V_{I} = V_{DD}$ | | | 1.0 | μΑ | |
| Input"Low" current | I _{IL3} | $V_I = 0 V$ | 2.0 | | 36. 0 | μΑ | 4 |
| Output"Low" voltage | V _{oL1} | $I_{0L} = 0.8 \text{m A}$ | | | 0.4 | V | |
| Output"High"voltage | V _{OH1} | $I_{0H} = -0.4 \text{m A}$ | V _{DD} -0.5 | | | V | 5 |
| Output"Low" voltage | V_{ol2} | $I_{0L} = 2.4 \text{m A}$ | | | 0.4 | V | |
| Output"High"voltage | ${ m V}_{ m OH2}$ | $I_{0H} = -1.2 \text{m A}$ | V _{DD} -0.5 | | | V | 6_ |

#1: Applied to Input pins (IC, ICU, ICD).

#2: Applied to Input pins (IC).

#3: Applied to Input pin (ICD).

#4: Applied to Input pins (ICU).

#5: Applied to Output pins (O2M).

#6: Applied to Output pins (06M).



6. Netlist and Testpatterns

Netlist

netlist name :CSUFB53.V

Testpattern

| AMTTGN_1300 | AMTTGN_s100 |
|------------------|-------------|
| AMTTGN_1301 | AMTTGN_s200 |
| AMTTGN_0000_0116 | AMTTGN_s301 |
| AMTTGN_o100_0116 | AMTTGN_s302 |
| AMTTGN_o200_0116 | AMTTGN_s303 |
| AMTTGN_o300 | AMTTGN_a101 |

These testpatterns are used for the final inspection of products by the appointed strobe points. The tester's frequency for the final inspection is $1 \mathrm{MHz}$.



7 Package and packing specification

[Applicability]

This specification applies to IC package which are to be delivered to Mobile Liquid Crystal Display Group SHARP CORPORATION.

1.Storage Conditions.

- 1-1. Storage conditions required before opening the dry packing.
 - Normal temperature : $5\sim40^{\circ}$ C
 - Normal humidity: 80% R.H. max.
- 1-2. Storage conditions required after opening the dry packing.

In order to prevent moisture absorption after opening, ensure the following storage conditions apply:

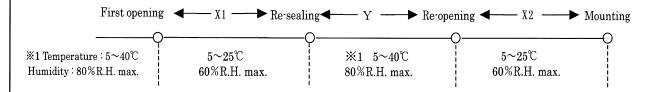
- (1) Storage conditions for one-time soldering. (Convection reflow*1, IR/Convection reflow.*1)
 - Temperature : 5~25°C
 - Humidity: 60% R.H. max.
 - · Period: 96 hours max. after opening.
- (2) Storage conditions for two-time soldering. (Convection reflow.*1, IR/Convection reflow.*1)
 - a. Storage conditions following opening and prior to performing the 1st reflow.
 - Temperature : 5~25°C
 - · Humidity: 60% R.H. max.
 - Period: 96 hours max. after opening.
 - b. Storage conditions following completion of the 1st reflow and prior to performing the 2nd reflow.
 - Temperature : 5~25°C
 - · Humidity: 60% R.H. max.
 - Period: 96 hours max. after completion of the 1st reflow.

1-3. Temporary storage after opening.

To re-store the devices before soldering, do so only once and use a dry box or place desiccant (with a blue humidity indicator) with the devices and perform dry packing again using heat-sealing.

The storage period, temperature and humidity must be as follows:

- (1) Storage temperature and humidity.
 - *1: External atmosphere temperature and humidity of the dry packing.



- (2) Storage period.
 - X1+X2: Refer to Section 1-2(1) and (2)a, depending on the mounting method.
 - Y : Two weeks max.

^{*1:}Air or nitrogen environment.



2. Baking Condition.

- (1) Situations requiring baking before mounting.
 - Storage conditions exceed the limits specified in Section 1-2 or 1-3.
 - Humidity indicator in the desiccant was already red (pink) when opened.
 - (Also for re-opening.)
- (2) Recommended baking conditions.
 - Baking temperature and period : $120+10/-0^{\circ}$ for $1\sim3$ hours.
 - The above baking conditions do not apply since the embossed carrier tape are not heat-resistant. Replace the devices on heat-resistant carrier.
- (3) Storage after baking.
 - After baking, store the devices in the environment specified in Section 1-2 and mount immediately.
- 3. Surface mount conditions.

The following soldering condition are recommended to ensure device quality.

- 3-1. Soldering.
- (1) Convection reflow or IR/Convection. (one-time soldering or two-time soldering in air or nitrogen environment)
 - Temperature and period:

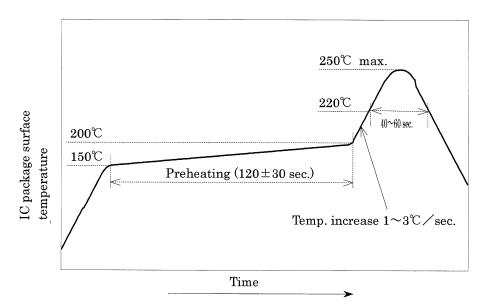
Peak temperature of 250° max.

Above 220°C for $40\sim60$ sec.

Preheat temperature of $150\sim200\%$ for 120 ± 30 sec.

Temperature increase rate of $1\sim 3\%$ /sec.

- · Measuring point : IC package surface.
- Temperature profile:

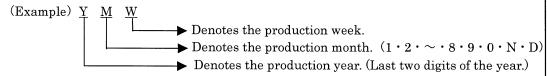


- 4. Condition for removal of residual flax.
- (1) Ultrasonic washing power: 25 watts / liter max.
- (2) Washing time: Total 1 minute max.
- (3) Solvent temperature: $15 \sim 40^{\circ}$ C

5. Package outline specification.

Refer to the attached drawing.

- 6. Markings.
 - 6-1. Marking details. (The information on the package should be given as follows.)
 - (1) Product name : 9FD53
 - (2) Company name : SHARP
 - (3) Date code

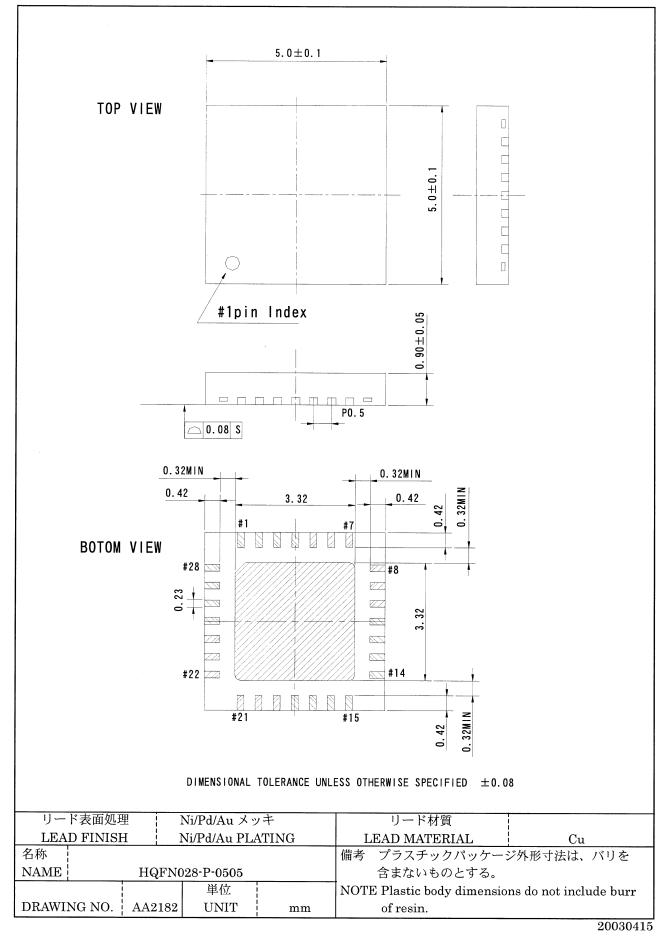


6-2. Marking layout.

The layout is shown in the attached drawing.

(However, this layout does not specify the size of the marking character and marking position.)





マークイメージ図 Marking image 9FD53 **SHARP** YMW Index Mark



7. Packing specifications (Embossed carrier tape specifications)

This standard applies to the embossed carrier tape specifications for ICs supplied by SHARP CORPORATION. SHARP's embossed carrier tape specifications are generally based on those described in JIS C 0806 (Japanese Industrial Standard) and EIA481A.

7-1. Tape structure

The embossed carrier tape is made of conductive plastic. The embossed portions of the carrier tape are filled with IC packages and a top covering tape is used to enclose them.

7-2. Taping reel and embossed carrier tape size

For the taping reel and embossed carrier tape sizes, refer to the attached drawing.

7-3.IC package enclosure direction in embossed carrier tape

The IC package enclosure direction in the embossed portion relative to the direction in which the tape is pulled is indicated by an index mark on the package (indicating the No. 1 pin) shown in the attached drawing.

7-4. Missing IC packages in embossed carrier tape

The number of missing IC packages in the embossed carrier tape per reel should not exceed Either 1 or 0.1 % of the total contained on the tape per reel, whichever is larger. There should never be more than two consecutive missing IC packages.

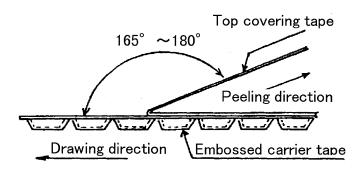
7-5. Tape joints

There is no joint in an embossed carrier tape.

7-6. Peeling strength of the top covering tape

Peeling strength must meet the following conditions.

- (1) Peeling angle at $165 \sim 180^{\circ}$.
- (2) Peeling speed at 300mm/min.
- (3) Peeling strength at $0.2 \sim 0.7 \,\mathrm{N}$ ($20 \sim 70 \,\mathrm{gf}$).





7-7. Packing

- (1) The top covering tape (leader side) at the leading edge of the embossed carrier tape, and the trailing edge of the embossed carrier tape, should both be held in place with paper adhesive tape at least 30 mm in length.
- (2) The leading and trailing edges of the embossed carrier tape should be left empty (with embossed portions not filled with IC packages) in the attached drawing.
- (3) The number of IC packages enclosed in the embossed carrier tape per reel should generally comply with the list given below.

| Number of IC Packages/ | Number of IC Packages/ | Number of IC Packages/ | | |
|------------------------|-----------------------------|------------------------------|--|--|
| Reel | Inner carton | Outer carton | | |
| 2500 devices / Reel | 2500 devices / Inner carton | 12500 devices / Outer carton | | |

7-8.Indications

The following should be indicated on the taping reel and the packing carton.

- · Part Number (Product Name) · Storage Quantity · Packed date
- · Manufacture's Name (SHARP)

Note: The IC taping direction is indicated by "EL" suffixed to the part number.

EL: Equivalent to "L" of the JIS C 0806 standard..

7-9. Protection during transportation

The IC packages should have no deformation and deterioration of their electrical Characteristics resulting from transportation.

8. Precautions for use.

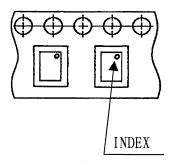
- Opening must be done on an anti-ESD treated workbench.
 All workers must also have undergone anti-ESD treatment.
- (2) The devices should be mounted the devices within one year of the date of delivery.



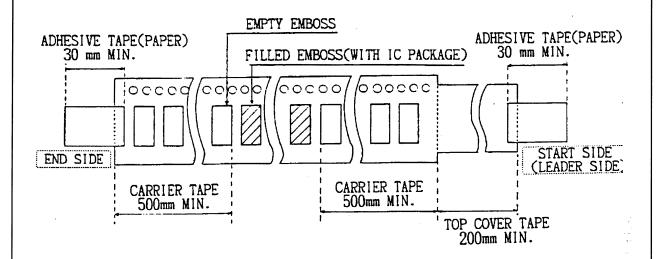
EMBOSS TAPING TYPE (EL)

IC TAPING DIRECTION

THE DRAWING DIRECTION OF TAPE



LEADER SIDE AND END SIDE OF TAPE



| 名称 | | | | | 備考 |
|--------|-------|----------|----------|-----|------|
| NAME | Emt | oss tapi | ng type(| EL) | NOTE |
| | | | 単位 | | |
| DRAWIN | G NO. | CV522 | UNIT | mm | |



